

## **Supplementary Material for:**

### **Absolute Doubly Differential Angular Sputtering Yields for 20 keV Kr<sup>+</sup> on Polycrystalline Cu**

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**Table S1** – Polar  $\theta_s$  and azimuthal  $\phi_s$  angle for the center of each collector, together with the measured mass gain  $\Delta m$ , uncertainty in the measured mass gain  $\sigma_{\Delta m}$ , absolute measured and SDTrimSP doubly differential sputtering yield  $(dY/d\Omega)_M$  and  $(dY/d\Omega)_S$ , respectively, and fractional difference between the measured and simulated yield  $\Delta(dY/d\Omega) = [(dY/d\Omega)_M - (dY/d\Omega)_S] / (dY/d\Omega)_S$ .

$\theta_s$ (degree)	$\phi_s$ (degree)	$\Delta m$ ( $\mu\text{g}$ )	$\sigma_{\Delta m}$ ( $\mu\text{g}$ )	$(dY/d\Omega)_M$ (atoms/ion/sr)	$(dY/d\Omega)_S$ (atoms/ion/sr)	$\Delta(dY/d\Omega)$
0.0	0.0	10.12	0.13	9.65	9.43	0.023
15.0	0.0	9.41	0.20	8.98	9.03	-0.006
15.0	60.0	10.03	0.25	9.56	8.75	0.093
15.0	120.0	9.05	0.41	8.63	8.54	0.010
15.0	180.0	8.63	0.17	8.23	8.39	-0.019
30.0	0.0	7.66	0.12	7.30	7.48	-0.023
30.0	28.4	7.76	0.08	7.40	7.39	0.001
30.0	56.8	8.41	0.18	8.02	7.19	0.116
30.0	85.2	8.44	0.07	8.05	6.99	0.151
30.0	113.6	7.60	0.11	7.25	6.84	0.060
30.0	142.0	6.73	0.13	6.42	6.77	-0.052
45.0	0.0	5.61	0.08	5.35	5.44	-0.017

45.0	20.5	5.86	0.07	5.59	5.45	0.025
45.0	41.0	6.18	0.11	5.90	5.27	0.119
45.0	61.5	6.23	0.07	5.94	5.20	0.141
45.0	82.0	6.90	0.09	6.58	5.01	0.314
45.0	102.5	6.39	0.07	6.10	4.98	0.224
45.0	123.0	5.30	0.07	5.05	4.71	0.072
45.0	143.5	5.13	0.11	4.89	4.57	0.071
60.0	0.0	2.77	0.12	2.64	3.17	-0.168
60.0	17.0	2.85	0.12	2.72	3.06	-0.111
60.0	34.0	3.10	0.06	2.95	3.19	-0.075
60.0	51.0	2.98	0.76	2.84	2.97	-0.044
60.0	68.0	3.62	0.13	3.45	2.87	0.202
60.0	85.0	3.96	0.11	3.77	2.69	0.402
60.0	102.0	3.74	0.10	3.57	2.77	0.285
60.0	119.0	3.49	0.11	3.32	2.58	0.286
60.0	136.0	3.50	0.04	3.33	2.52	0.321
60.0	153.0	3.77	0.08	3.59	2.51	0.431

75.0	0.0	0.01	0.62	0.01	1.21	-0.990
75.0	14.5	0.40	0.16	0.38	1.20	-0.680
75.0	29.0	0.88	0.12	0.84	1.24	-0.320
75.0	43.5	0.82	0.06	0.78	1.20	-0.349
75.0	58.0	1.22	0.19	1.16	1.18	-0.021
75.0	72.5	1.86	0.10	1.77	1.15	0.537
75.0	87.0	1.98	0.07	1.89	1.08	0.741
75.0	101.5	1.54	0.09	1.46	1.00	0.461
75.0	116.0	1.71	0.06	1.63	1.09	0.494
75.0	130.5	1.59	0.08	1.52	0.98	0.545
75.0	145.0	1.74	0.09	1.66	0.97	0.717
75.0	159.5	1.88	0.08	1.79	0.99	0.813